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P-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$ Typ.	$G_{(on)}(\Omega)$ Typ. $I_{D}(A)$ Q			
- 40	0.009 at V _{GS} = - 10 V	- 50 ^d	45 nC		
	0.014 at V _{GS} = - 4.5 V	- 40 ^d	45 110		

FEATURES

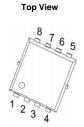
- DT-Trench Power MOSFET
- 100 % R_a and UIS Tested

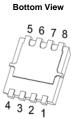
RoHS COMPLIANT

APPLICATIONS

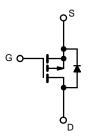
- Battery, Load and Adaptor Switches
 - Notebook Computers
 - Notebook Battery Packs

PDFN 3.3x3.3









P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T	$_{A}$ = 25 °C, unless oth	erwise noted)		
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	- 40	V	
Gate-Source Voltage		V _{GS}	± 20	
	T _C = 25 °C		- 50 ^d	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	₋	- 40 ^d	
Continuous Brain Gunent (1) = 100 °C)	T _A = 25 °C	l _D	- 24 ^{a, b}	
	T _A = 70 °C		- 16 ^{a, b}	A
Pulsed Drain Current (t = 100 μs)		I _{DM}	- 200	
Continuous Source-Drain Diode Current	T _C = 25 °C	l _a	- 50 ^d	
Continuous Source-Diairi Diode Current	T _A = 25 °C	I _S	- 4.1 ^{a, b}	
Avalanche Current	L = 0.1 mH	I _{AS}	- 45	
Single-Pulse Avalanche Energy		E _{AS}	92	mJ
	T _C = 25 °C		96	
Maximum Power Dissipation	T _C = 70 °C	P _D	51	W
Maximum Fower Dissipation	T _A = 25 °C	υ υ	5.5 ^{a, b}	VV
	T _A = 70 °C		3.2 ^{a, b}	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	
Soldering Recommendations (Peak Temperature) ^{e, f}		260	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{a, c}	t ≤ 10 s	R _{thJA}	21	25	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	2.1	2.6]	

Notes:

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- c t = 2s
- d. See solder profile The PDFN3.3X3.3 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 80 °C/W.



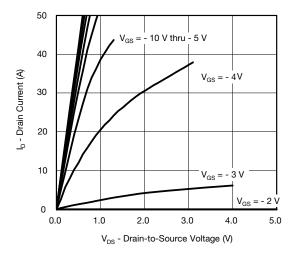


Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static					1		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0$, $I_D = -250 \mu A$	- 40			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 050 vA		- 22		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = - 250 μA		4.1			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	- 1		- 3	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = - 32 V, V _{GS} = 0 V			- 1		
		V _{DS} = - 32 V, V _{GS} = 0 V, T _J = 55 °C			- 5	μΑ	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge -10 \text{ V}, V_{GS} = -10 \text{ V}$	- 50			Α	
Drain-Source On-State Resistance ^a	_	V _{GS} = - 10 V, I _D = - 15 A		0.009	0.012	Ω	
	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 10 A		0.014	0.018		
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 10 V, I _D = - 15 A		60	0.0.0	S	
Dynamic ^b							
Input Capacitance	C _{iss}			3300	5800		
Output Capacitance	C _{oss}	$V_{DS} = -32 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		550	0000	pF	
Reverse Transfer Capacitance	C _{rss}			238			
·		V _{DS} = - 32 V, V _{GS} = - 10 V, I _D = - 10 A		45		+	
Total Gate Charge	Q_g	BS 1 7 GS 1 7 B		23		nC	
Gate-Source Charge	Q _{gs}	V _{DS} = - 32 V, V _{GS} = - 4.5 V, I _D = - 10 A		11			
Gate-Drain Charge	Q _{gd}			18			
Gate Resistance	R _g	f = 1 MHz	0.5	2.5	4.8	Ω	
Turn-On Delay Time	t _{d(on)}			18			
Rise Time	t _r	$V_{DD} = -32 \text{ V, R}_{L} = 1.5 \Omega$		13		-	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -10 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		55			
Fall Time	t _f			11		1	
Turn-On Delay Time	t _{d(on)}			63		ns	
Rise Time	t _r	$V_{DD} = -32 \text{ V, R}_{1} = 1.5 \Omega$		65		- - -	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -10 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_q = 1 \Omega$		50			
Fall Time	t _f			22			
Drain-Source Body Diode Characterist							
Continous Source-Drain Diode Current	I _S	T _C = 25 °C			- 50	Α .	
Pulse Diode Forward Current (100 μs)	I _{SM}				- 200	- A	
Body Diode Voltage	V _{SD}	I _S = -3 A, V _{GS} = 0		- 0.75	- 1.20	V	
Body Diode Reverse Recovery Time	t _{rr}			23	46	ns	
ody Diode Reverse Recovery Charge Q_{rr} everse Recovery Fall Time t_a $I_F = -10 \text{ A}, \text{ dI/dt} = 100 \text{ A/µs}, T_J = 25 ^{\circ}\text{C}$			12	24	nC		
			9		ns		
Reverse Recovery Rise Time	t _b	t _b		14		1 115	

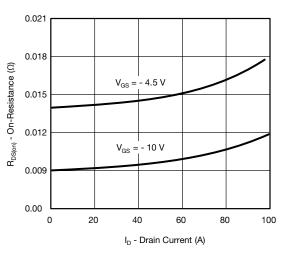
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

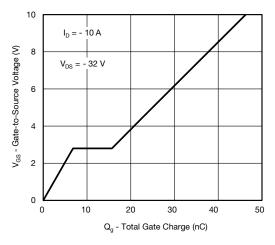




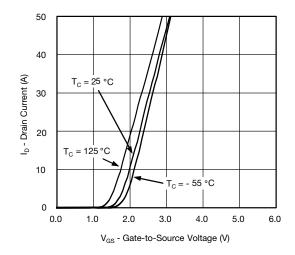
Output Characteristics



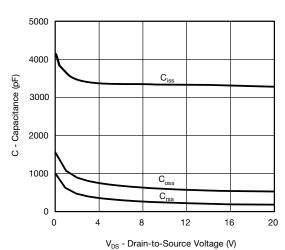
On-Resistance vs. Drain Current



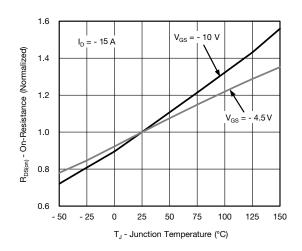
Gate Charge



Transfer Characteristics

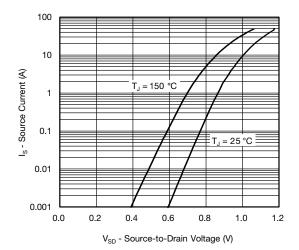


Capacitance

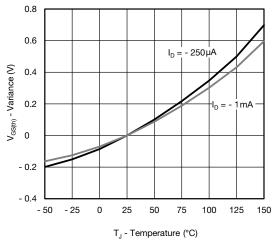


On-Resistance vs. Junction Temperature

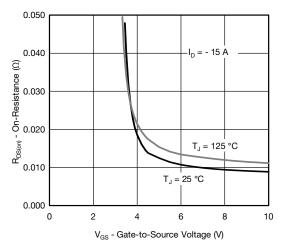




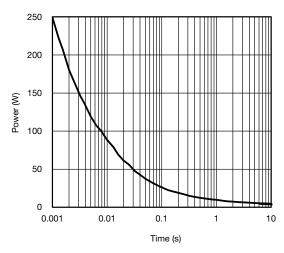
Source-Drain Diode Forward Voltage



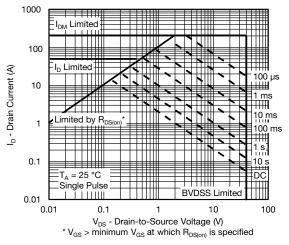
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage

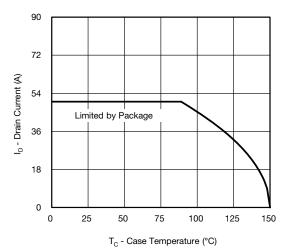


Single Pulse Power, Junction-to-Ambient

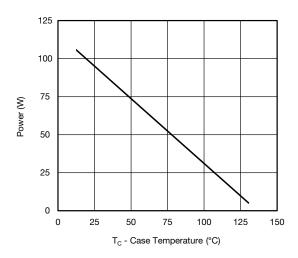


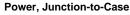
Safe Operating Area

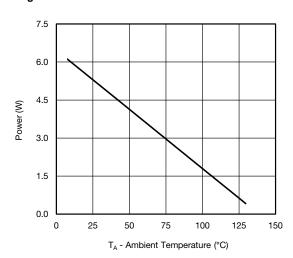




Current Derating*



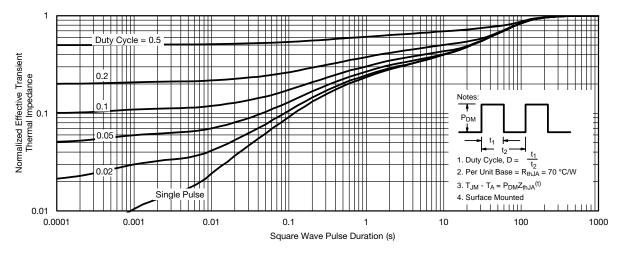




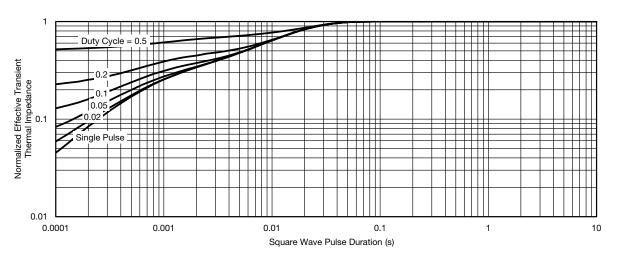
Power Derating, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case





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